

**Web**Results 1 - 10 of about 40 for "shuffle distance". (0.30 seconds)**push shuffle distance**

... push **shuffle distance**. From: Remote Name: 156.56.123.130. Comments. I know this is a very relative question, but about what is the ratio between the ...

[www.jkdwednite.com/forums/\\_forums/00001223.htm](http://www.jkdwednite.com/forums/_forums/00001223.htm) - 3k - [Cached](#) - [Similar pages](#)

**Re: push shuffle distance**

Re: push **shuffle distance**. From: Brent Lance Remote Name: 12.21.233.239. Comments. I use the step and slide to manipulate distance and keep a fighting ...

[www.jkdwednite.com/forums/\\_forums/00001224.htm](http://www.jkdwednite.com/forums/_forums/00001224.htm) - 4k - [Cached](#) - [Similar pages](#)

**GMOS: Nod & Shuffle**

... For example, for a single-band Nod & Shuffle observation the **shuffle distance** is +1536 ... image with 1 arcsec slits the **shuffle distance** is 14 pixels. ...

[www.gemini.edu/sciops/instruments/gmos/gmosNodShuffle.html](http://www.gemini.edu/sciops/instruments/gmos/gmosNodShuffle.html) - 28k - [Cached](#) - [Similar pages](#)

**[PDF] Microsoft PowerPoint - cement-post-icpr.ppt**

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... **Shuffle Distance**. **Shuffle Distance**. Intensity histogram intersection can also be covered. Intensity histogram intersection can also be covered ...

[www.cemnet.ntu.edu.sg/presentation/slides\\_chamtajen.pdf](http://www.cemnet.ntu.edu.sg/presentation/slides_chamtajen.pdf) - [Similar pages](#)

**File Index**

... core/vil/algo/vil\_abs\_shuffle\_distance.h [code], Compute **shuffle distance** between two images. core/vil/algo/vil\_abs\_shuffle\_distance.txx [code] ...

[paine.wiau.man.ac.uk/pub/doc\\_vxl/core/vil/html/files.html](http://paine.wiau.man.ac.uk/pub/doc_vxl/core/vil/html/files.html) - 56k - Mar 8, 2005 - [Cached](#) - [Similar pages](#)

**vil\_abs\_shuffle\_distance.txx File Reference**

... Compute **shuffle distance** between two images. Author:: Tim Cootes ...  
Computes **shuffle distance** between image1 and image2. ...

[paine.wiau.man.ac.uk/pub/doc\\_vxl/core/vil/html/vil\\_abs\\_shuffle\\_distance\\_8txx.html](http://paine.wiau.man.ac.uk/pub/doc_vxl/core/vil/html/vil_abs_shuffle_distance_8txx.html) - 8k - [Cached](#) - [Similar pages](#)

[ [More results from paine.wiau.man.ac.uk](http://paine.wiau.man.ac.uk/) ]

**Gemini/NOAO newsletter article**

... These are: (i) the **shuffle distance**, Y; (ii) the sub-integration time and (iii) the ... 2a): The **shuffle distance** is small and the sky image is recorded ...

[www.ociw.edu/lcirs/public/GeminiNewsletter.htm](http://www.ociw.edu/lcirs/public/GeminiNewsletter.htm) - 51k - [Cached](#) - [Similar pages](#)

**[PDF] Probabilistic Tracking with Exemplars in a Metric Space**

File Format: PDF/Adobe Acrobat - [View as HTML](#)

... on binary edge images, and tracking mouth movements by means of a **shuffle distance**. ... tracking based on the **shuffle distance** continues largely ...

[research.microsoft.com/vision/cambridge/papers/toyama\\_ijcv02.pdf](http://research.microsoft.com/vision/cambridge/papers/toyama_ijcv02.pdf) - [Similar pages](#)

**[PDF] Probabilistic Tracking in a Metric Space**

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... after image warp based on optic flow, (h) **shuffle distance** as described in text.  
... mshuffle.mpg shows tracking using the **shuffle distance**. ...

[research.microsoft.com/vision/papers/ICCV2001ToyamaBlake/ICCV2001ToyamaBlakeColor.pdf](http://research.microsoft.com/vision/papers/ICCV2001ToyamaBlake/ICCV2001ToyamaBlakeColor.pdf) -

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**1 Simple model for space-charge region capacitance of an exponential constant p-n junction**

*Ho, F.D.;*

Electronics Letters , Volume: 26 , Issue: 25 , 6 Dec. 1990

Pages:2063 - 2065

[\[Abstract\]](#) [\[PDF Full-Text \(212 KB\)\]](#) **IEE JNL**

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**2 A conservative theory for long term reliability growth prediction**

*Bishop, P.G.; Bloomfield, R.E.;*

Software Reliability Engineering, 1996. Proceedings., Seventh International Symposium on , 30 Oct.-2 Nov. 1996

Pages:308 - 317

[\[Abstract\]](#) [\[PDF Full-Text \(764 KB\)\]](#) **IEEE CNF**

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**3 Bussgang-zero crossing equalization: an integrated HOS-SOS approach**

*Jacovitti, G.; Panci, G.; Scarano, G.;*

Signal Processing, IEEE Transactions on [see also Acoustics, Speech, and Signal Processing, IEEE Transactions on] , Volume: 49 , Issue: 11 , Nov. 2001

Pages:2798 - 2812

[\[Abstract\]](#) [\[PDF Full-Text \(397 KB\)\]](#) **IEEE JNL**

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**4 Analysis of multiexponential transient signals using interpolation-based deconvolution and parametric modeling techniques**

*Salami, M.J.E.; Ismail, Z.;*

Industrial Technology, 2003 IEEE International Conference on , Volume: 1 , 1 Dec. 2003

Pages:271 - 276 Vol.1

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